

## EAST Search History

| Ref # | Hits    | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|---------|--|---|------------------|---------|------------------|
| L2    | 55      | ((CHUNG-SAM) near2 (JUN)).INV.   | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR               | ON      | 2007/02/16 13:14 |
| L3    | 59      | ((SANG-MUN) near2 (CHON)).INV.   | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR               | ON      | 2007/02/16 13:19 |
| L4    | 24      | ((SUN-YONG) near2 (CHOI)).INV.   | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR               | ON      | 2007/02/16 13:21 |
| L5    | 35      | ((DONG-JIN) near2 (PARK)).INV.   | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR               | ON      | 2007/02/16 13:22 |
| L6    | 8       | ((JEONG-HYUN) near2 (CHOI)).<br>INV.   | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR               | ON      | 2007/02/16 13:24 |
| S1    | 37073   | fft or fast adj fourier adj transform  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND              | ON      | 2007/02/15 12:57 |
| S2    | 37073   | fft or (fast adj fourier adj<br>transform)                                     | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND              | ON      | 2007/02/15 12:57 |
| S3    | 69458   | (scanning adj electron adj<br>microscope) or (electron adj<br>microscope)      | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND              | ON      | 2007/02/15 12:58 |
| S4    | 332     | S2 and S3  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND              | ON      | 2007/02/15 12:58 |
| S5    | 3245791 | (sample) or (wafer) or (IC) or<br>(integrated adj circuit) or (IC adj<br>chip) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND              | ON      | 2007/02/15 13:00 |

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|     |       |   |   |     |    |                  |
|-----|-------|---|---|-----|----|------------------|
| S6  | 303   | S4 and S5   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND | ON | 2007/02/15 13:00 |
| S7  | 69630 | (inspect\$3 or analyzing or<br>determining or finding) same<br>(defects or abnormalities)                                 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND | ON | 2007/02/15 13:01 |
| S8  | 74077 | (inspect\$3 or analyzing or<br>determining or finding or<br>discrimi\$5) same (defects or<br>abnormalities)               | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND | ON | 2007/02/15 13:02 |
| S9  | 69    | S6 and S8   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND | ON | 2007/02/15 13:02 |
| S10 | 63    | etching same trace same (line adj<br>width)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | AND | ON | 2007/02/15 13:04 |
| S12 | 7     | ("4242635"   "4466746"  <br>"4668916"   "4682857"  <br>"6121059"   "6559670"  <br>"6657447").PN. OR ("6842021").<br>URPN. | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR  | ON | 2007/02/15 13:19 |